

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/519,216 WANG ET AL.	
		Examiner	Art Unit CHIH-MIN KAM	1656 Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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